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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/599,284	09/25/2006	Jan Bernd Lugtenburg	304-861	6488
30448 7590 03/10/2009 AKERMAN SENTERFITT			EXAMINER	
P.O. BOX 3188		KUNDU, SUJOY K		
WEST PALM BEACH, FL 33402-3188		58	ART UNIT	PAPER NUMBER
			2863	
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Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

	Application No.	Applicant(s)			
	10/599,284	LUGTENBURG, JAN BERND			
Office Action Summary	Examiner	Art Unit			
	SUJOY K. KUNDU	2863			
The MAILING DATE of this communication app Period for Reply	ears on the cover sheet with the c	orrespondence address			
A SHORTENED STATUTORY PERIOD FOR REPLY WHICHEVER IS LONGER, FROM THE MAILING DA - Extensions of time may be available under the provisions of 37 CFR 1.13	ATE OF THIS COMMUNICATION	l.			
 after SIX (6) MONTHS from the mailing date of this communication. If NO period for reply is specified above, the maximum statutory period w Failure to reply within the set or extended period for reply will, by statute, Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b). 	cause the application to become ABANDONEI	O (35 U.S.C. § 133).			
Status					
Responsive to communication(s) filed on <u>25 Secondary</u> This action is FINAL . 2b) ☑ This Since this application is in condition for allowar closed in accordance with the practice under Expression in the Expression in	action is non-final. nce except for formal matters, pro				
Disposition of Claims					
4) ☐ Claim(s) 1-21 is/are pending in the application. 4a) Of the above claim(s) is/are withdraw 5) ☐ Claim(s) is/are allowed. 6) ☐ Claim(s) 1-21 is/are rejected. 7) ☐ Claim(s) is/are objected to. 8) ☐ Claim(s) are subject to restriction and/or	vn from consideration.				
Application Papers					
9)☐ The specification is objected to by the Examiner.					
10)☐ The drawing(s) filed on is/are: a)☐ accepted or b)☐ objected to by the Examiner.					
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).					
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d). 11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.					
Priority under 35 U.S.C. § 119					
12)⊠ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a)⊠ All b)□ Some * c)□ None of:					
1. Certified copies of the priority documents have been received.					
2. Certified copies of the priority documents have been received in Application No					
3. Copies of the certified copies of the priority documents have been received in this National Stage					
application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received.					
Attachment(s)	_				
1) X Notice of References Cited (PTO-892) 4) Interview Summary (PTO-413) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) Paper No(s)/Mail Date					
Notice of Draitsperson's Patent Drawing Review (PTO-946) Information Disclosure Statement(s) (PTO/SB/08) Paper No(s)/Mail Date 09/25/2006; 12/11/2006. 5) Notice of Informal Patent Application Other:					

DETAILED ACTION

Claim Objections

Claims 3-5, 7, 9, and 21 objected to because of the following informalities:

These claims use the word "substantially," which makes the claim indefinite.

Appropriate correction is required. Furthermore, Claim 3 uses the word "vicinity of the measurement," which is also indefinite.

Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.

Claims 1-7, 9, 11-15, 17-21 are rejected under 35 U.S.C. 102(b) as being anticipated by Takagi et al. (4,721,388).

With regards to Claim 1, 11, Takagi teaches a method for measuring a measurement object having at least one reference structure for defining an object-fixed object coordinate system, with the aid of a measuring system comprising at least one sensor system for recording a contour of the measurement coordinate system, the method comprising the following steps:

positioning the measurement object in a measurement position in the coverage range of the sensor system (Abstract, Column 3, Lines 41-52);

establishing the position of the object coordinate system by means of a reference structure (Column 4, Lines 30-32);

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linking the object coordinate system with the measurement coordinate system (Figure 5, Column 4, Lines 47-53);

rotating the sensor system about a rotation axis relative to the measurement object for determining contour data (Figure 4, Column 4, Lines 13-26); and processing the contour data, whilst taking account of the position of the object coordinate system in an evaluation unit (Column 4, Lines 13-26).

With regards to Claim 2, 12, Takagi teaches the method wherein during the measurement, the measurement object is so fixed by a centering device that accessibility to the reference structure is not impeded (Figure 1, Column 2, Lines 55-58).

With regards to Claim 3, Takagi teaches the method wherein the measurement object is fixed in the measurement position in such a way that the reference structure is accessible for establishing the measurement object position (Figure 1, Column 2, Lines 55-58), the measurement object being substantially rotation-like with respect to a measurement object axis (Column 2, Line 60 - Column 3, Line 9), wherein the reference structure is positioned within the outer contour of the measurement object in the vicinity of the measurement object axis and a centering device for centering the measurement object acts on the outer contour of the measurement object (Column 2, Line 60 - Column 3, Line 9).

With regards to Claim 4, Takagi teaches the method wherein a reference device for establishing the position of the object coordinate system scans the substantially freely accessible reference structure (Column 4, Lines 30-43).

With regards to Claim 5, 13, Takagi teaches the method wherein the reference device scans in noncontacting ("light spot detecting sensor") manner the substantially freely accessible reference structure (Column 4, Lines 30-43).

With regards to Claim 6, 14, Takagi teaches the method, wherein a reference device performs a mechanical orientation of the measurement object by means of the reference system for establishing the position of the object coordinate system. (Figure 5, Column 3, Lines 53-65).

With regards to Claim 7, 15, Takagi teaches the method wherein a shape and/or position variation of at least one measurement object surface portion provided for engagement on an object surface (Column 4, Lines 13-26).

With regards to Claim 9, Takagi teaches the method, wherein the measurement object conveyed substantially linearly between an insertion opening and a discharge opening of the measurement system (Figure 4).

With regards to Claim 17, Takagi teaches the device wherein the reference device is arranged in rotary manner substantially coaxially to a rotation axis of the sensor system (Figures 3-4, Column 3, Lines 53-65).

With regards to Claim 18, Takagi teaches the device wherein integration takes place into a conveying device, particularly a linear conveying device (Column 4, Lines 39-43).

With regards to Claim 19, Takagi teaches the device wherein there are size determination means for a basic positioning of the sensor system and/or reference device (Column 4, Lines 13-26).

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With regards to Claim 20, Takagi teaches the method wherein the reference structure is measured (Column 4, Lines 13-26).

With regards to Claim 21, Takagi teaches the method wherein the measurement object is conveyed substantially perpendicular to the sensor system rotation axis (Figure 4).

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 8 and 16 are rejected under 35 U.S.C. 103(a) as being unpatentable over Takagi et al. (4,721,388) in view of Martinschledde et al. (US 2006/0158663).

With regards to Claim 8 and 16Takagi is silent with regards to the limitation of the method wherein a marking is made on the measurement object defining a characteristic measurement point by a marking device connected to the sensor system.

Martinschledde teaches the limitation of the method wherein a marking is made on the measurement object defining a characteristic measurement point by a marking device connected to the sensor system (Paragraph 33).

It would have been obvious to one of ordinary skill in the art at the time the invention was made to include the limitation of the method wherein a marking is made on the measurement object defining a characteristic measurement point by a marking device connected to the sensor system as taught by Martinschledde into Takagi for the

purpose of properly alignment on the measurement object to accurately measure the contour of the object.

Claim 10 is rejected under 35 U.S.C. 103(a) as being unpatentable over Takagi et al (4,721,388) in view of Prinzhausen et al. (US 2003/003898948).

Takagi is silent with regards to wherein measurement data of the sensor system are linked with measurement data of the reference device for determining wall thickness.

Prinzhausen teaches wherein measurement data of the sensor system are linked with measurement data of the reference device for determining wall thickness (Paragraph 22).

It would have been obvious to one of ordinary skill in the art at the time the invention was made to include wherein measurement data of the sensor system are linked with measurement data of the reference device for determining wall thickness as taught by Prinzhausen into Takagi for the purpose of accurately measuring different specification of the object.

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to SUJOY K. KUNDU whose telephone number is (571)272-8586. The examiner can normally be reached on M-F 9-5.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Drew Dunn can be reached on 571-272-2312. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

/S. K. K./ Examiner, Art Unit 2863 /Tung S. Lau/ Primary Examiner, Art Unit 2863 March 9, 2009